

**Notice of References Cited**

Application/Control No.

10/532,757

Applicant(s)/Patent Under  
Reexamination  
JACKSON ET AL.

Examiner

STEVEN KIM

Art Unit

3685

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,256,773 B1	07-2001	Bowman-Amuah, Michel K.	717/121
*	B	US-2001/0044781 A1	11-2001	Shutes, Christina S.	705/59
*	C	US-2002/0129221 A1	09-2002	Borgia et al.	712/1
*	D	US-2003/0229581 A1	12-2003	Green et al.	705/38
*	E	US-6,735,701 B1	05-2004	Jacobson, Andrea M.	726/1
*	F	US-2005/0071174 A1	03-2005	Leibowitz et al.	705/001
*	G	US-6,912,502 B1	06-2005	Buddle et al.	705/1
*	H	US-7,003,560 B1	02-2006	Mullen et al.	709/223
*	I	US-2006/0293942 A1	12-2006	Chaddha et al.	705/008
*	J	US-7,197,466 B1	03-2007	Peterson et al.	705/1
*	K	US-7,430,590 B1	09-2008	Rive et al.	709/220
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.